



# **VACANCY-IMPURITY INTERACTIONS IN ION-IMPLANTED SILICON**

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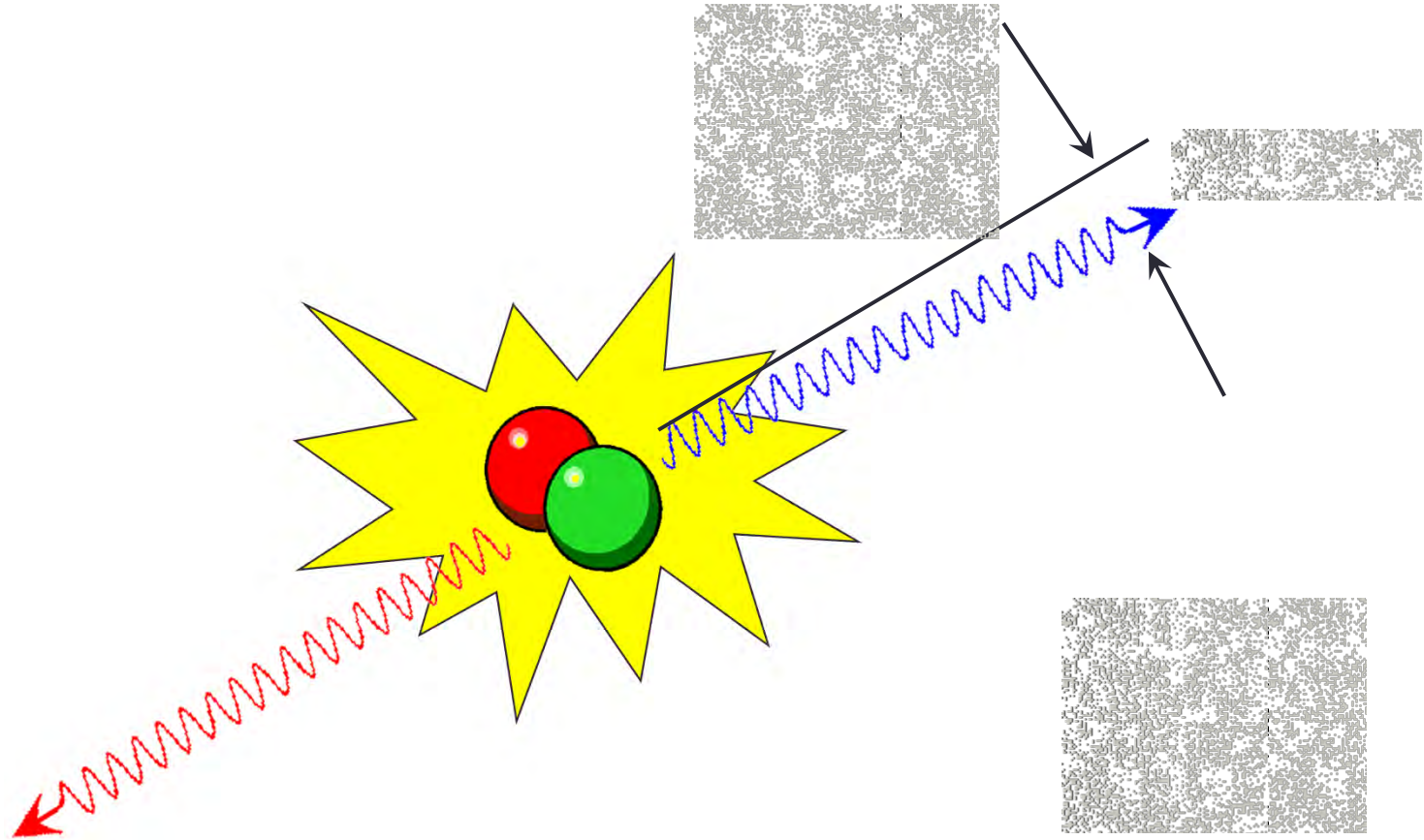
# Outline

- **Ion induced defects**
- **Positron annihilation**
- **Chemical “fingerprints”**
- **Migration energies**

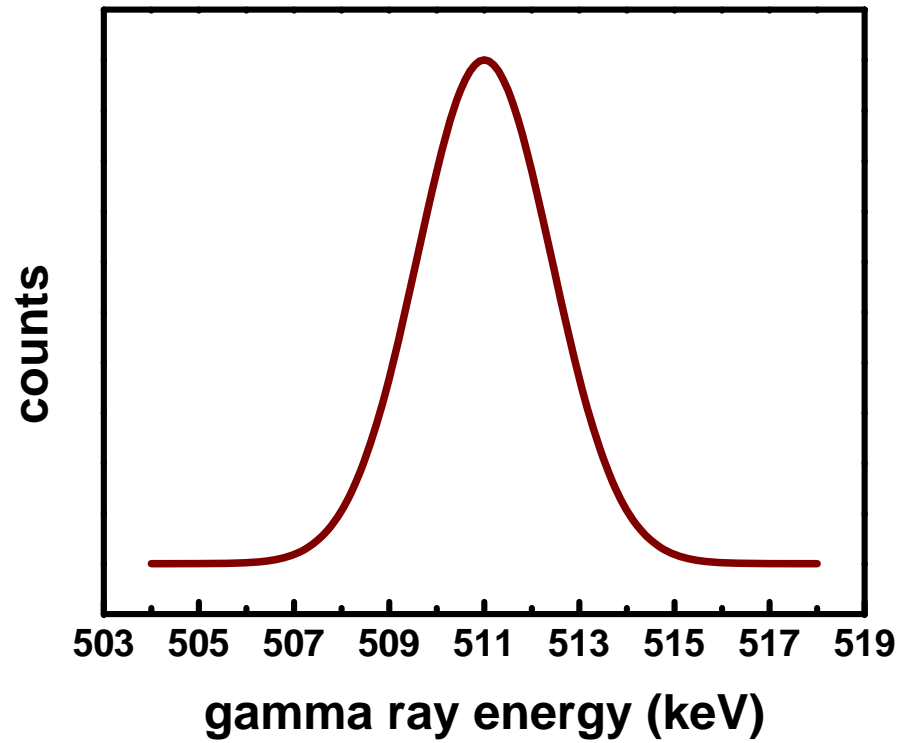
# Vacancy production

- silicon implantation into silicon at 500keV generates ~2900 vacancy-interstitial pairs per ion (SRIM)
- silicon monovacancies are mobile at room temperature
- vacancies pair with each other or with impurities (dopants, oxygen)
- ~at room temperature, ~90% of the vacancies produced recombine with interstitials

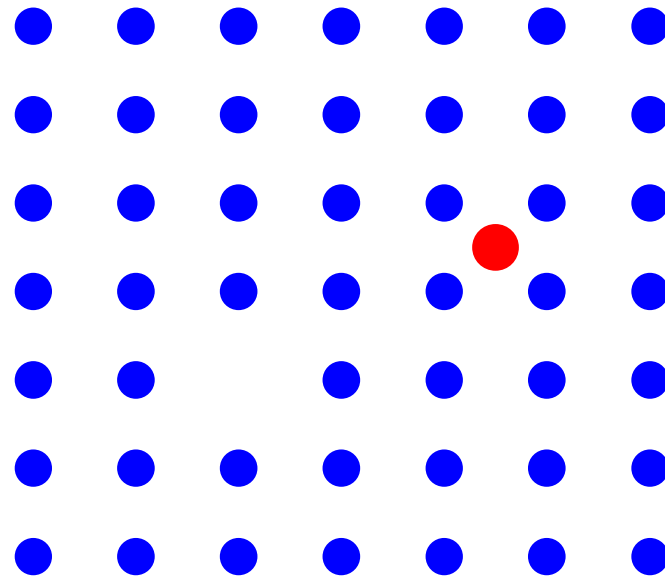
# Positron Annihilation



# Gamma ray spectrum



# Positrons are trapped by defects



# “S”harpness parameter

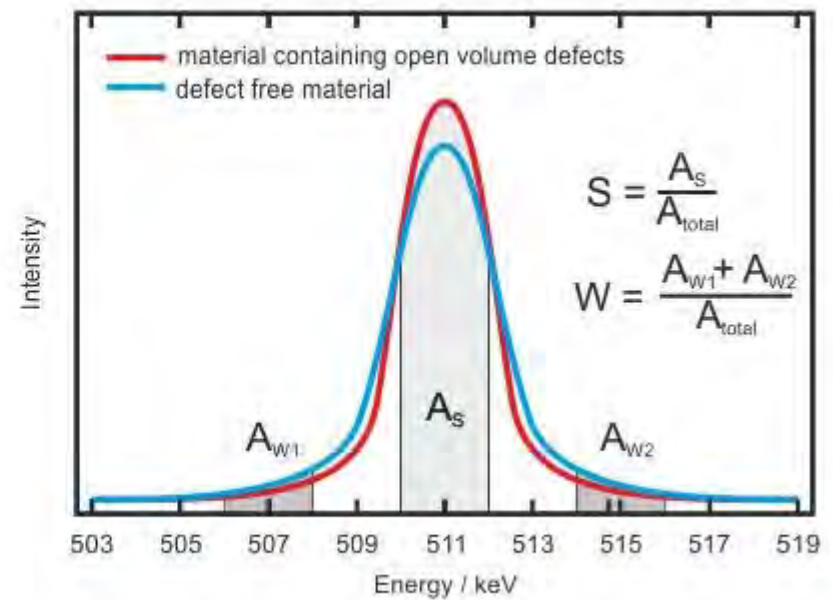
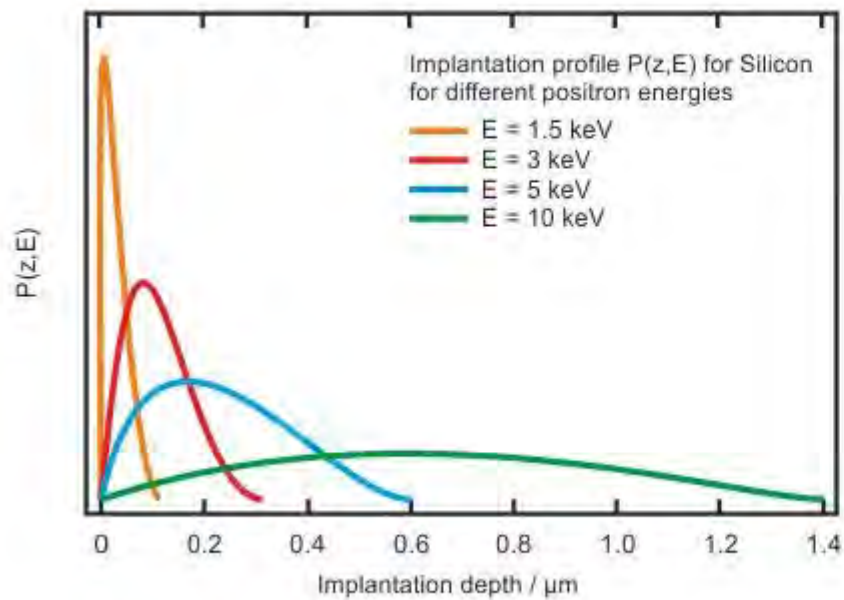
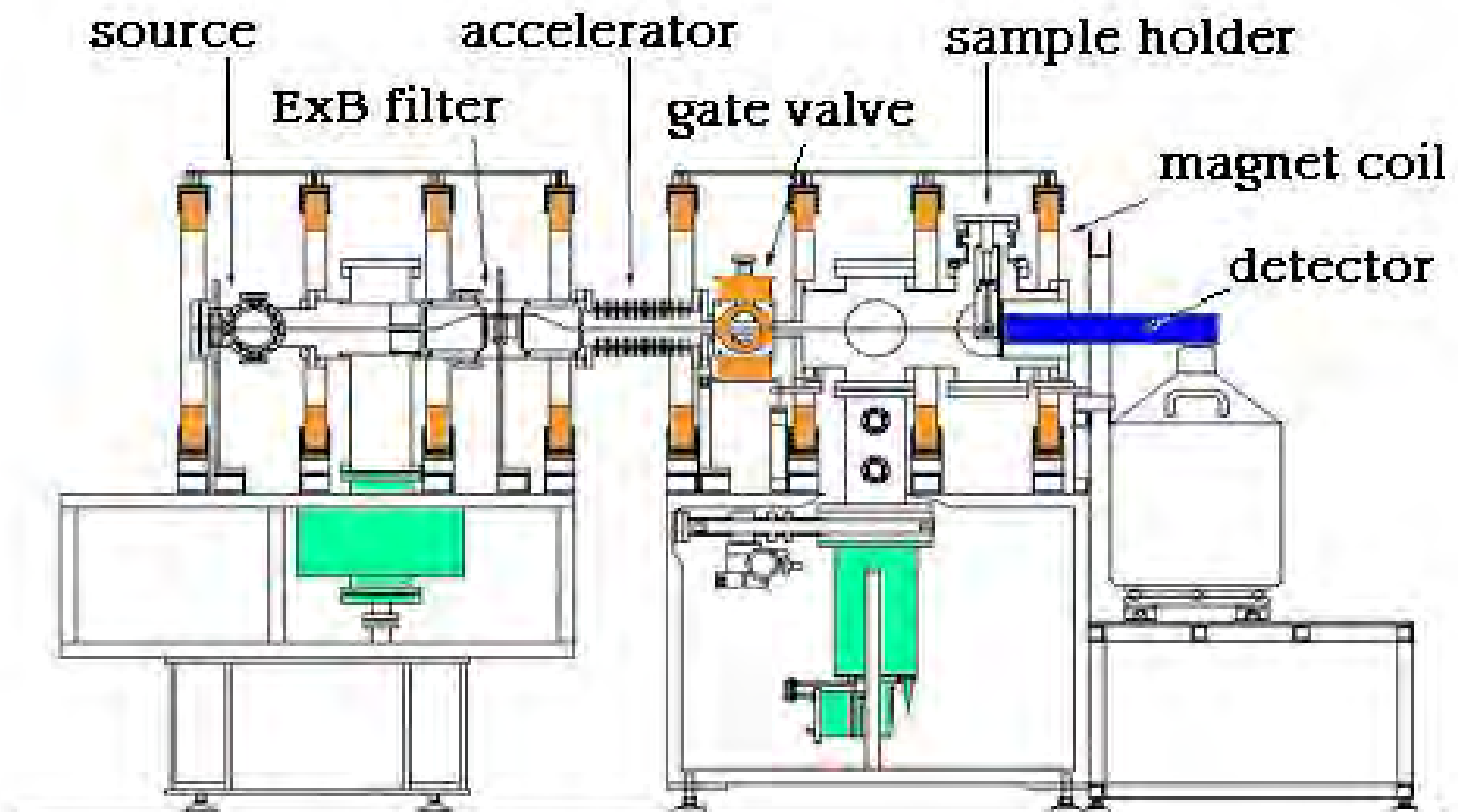


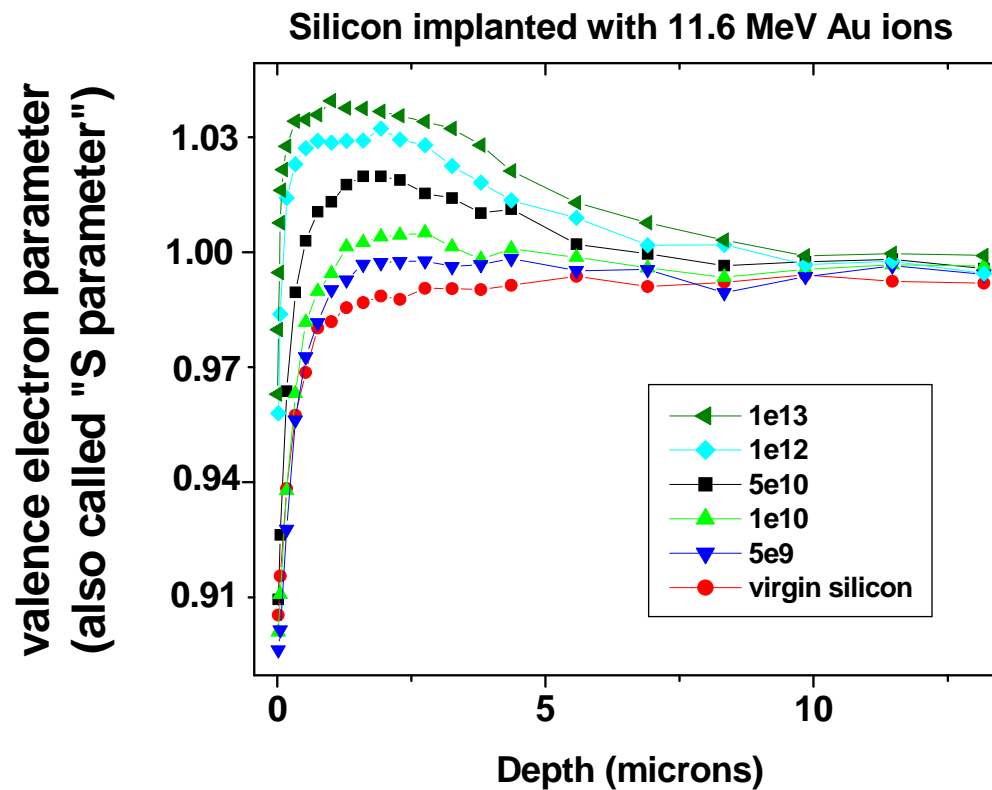
Figure by Maik Butterling

# Positron accelerator

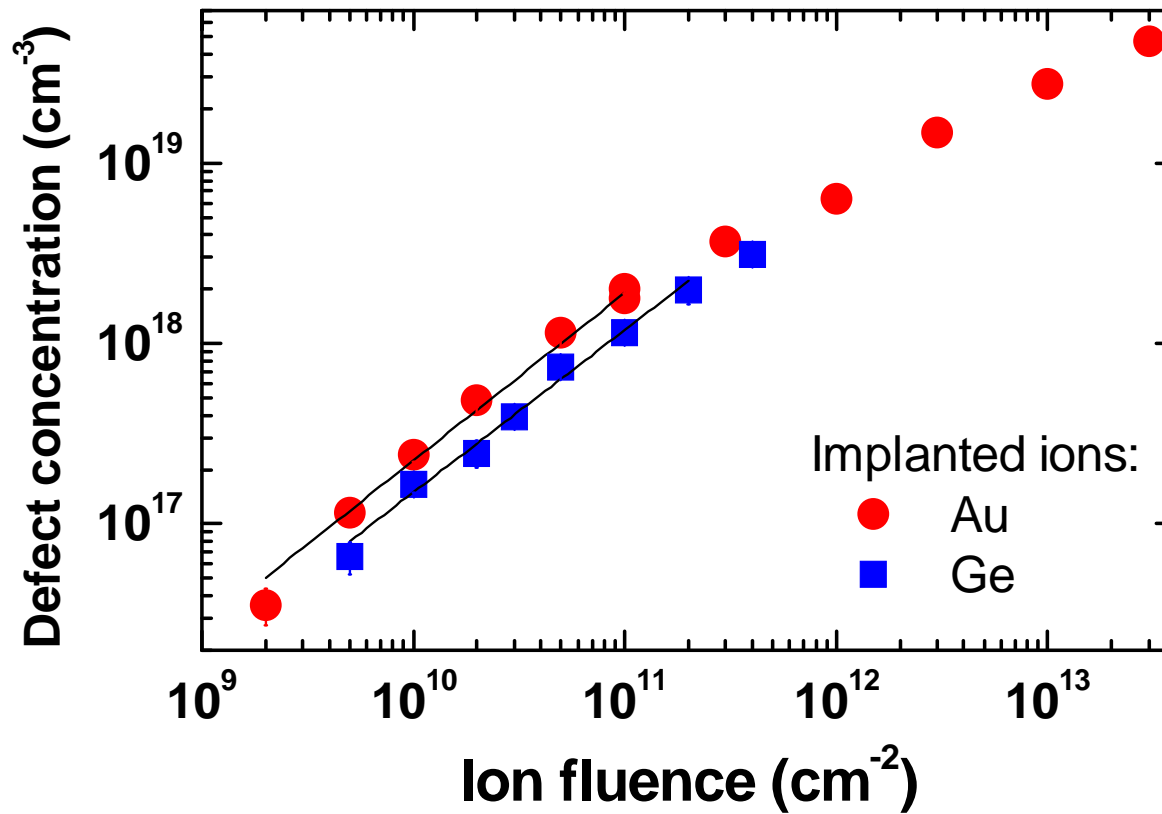




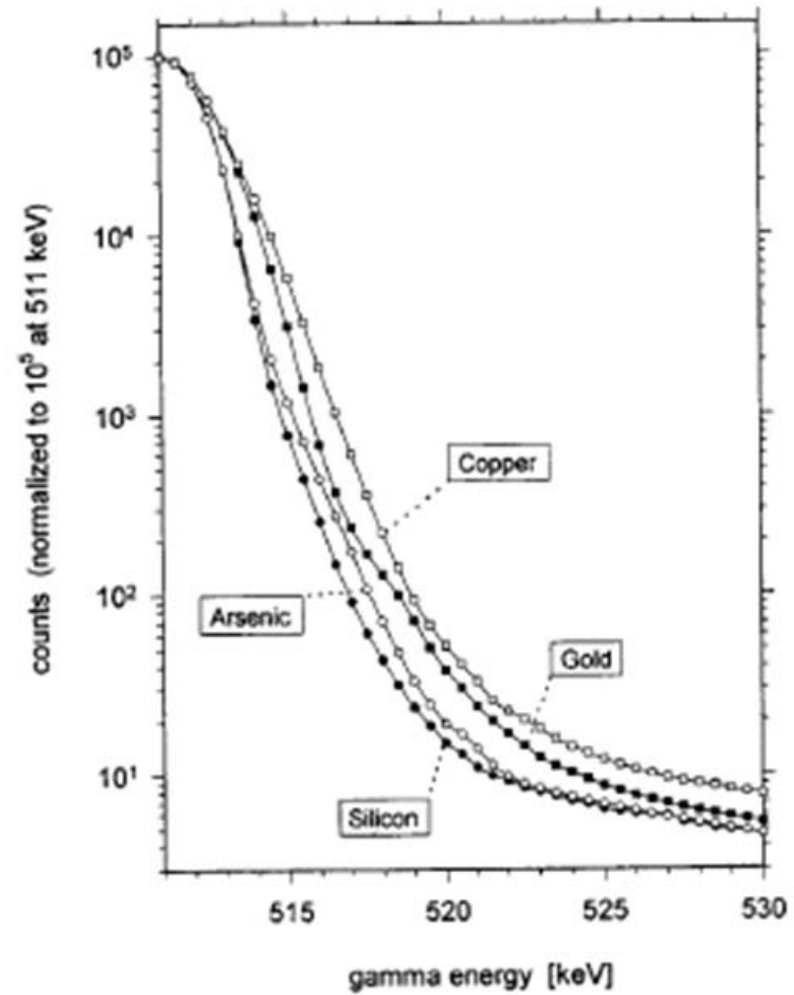
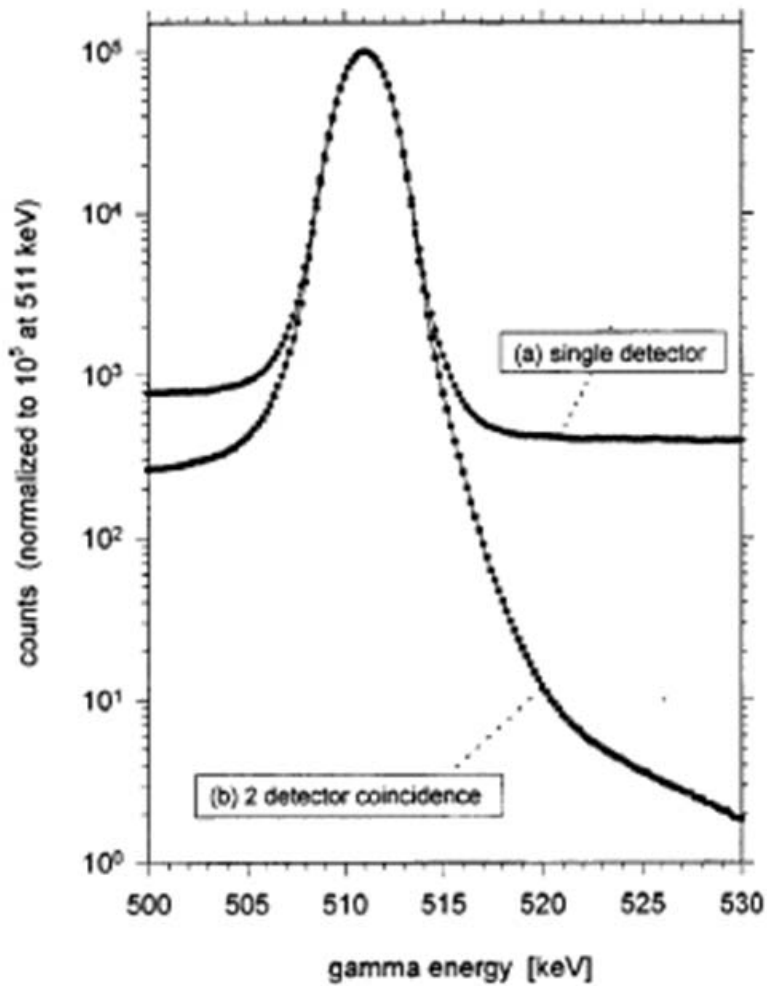
# Example: ion-implanted silicon



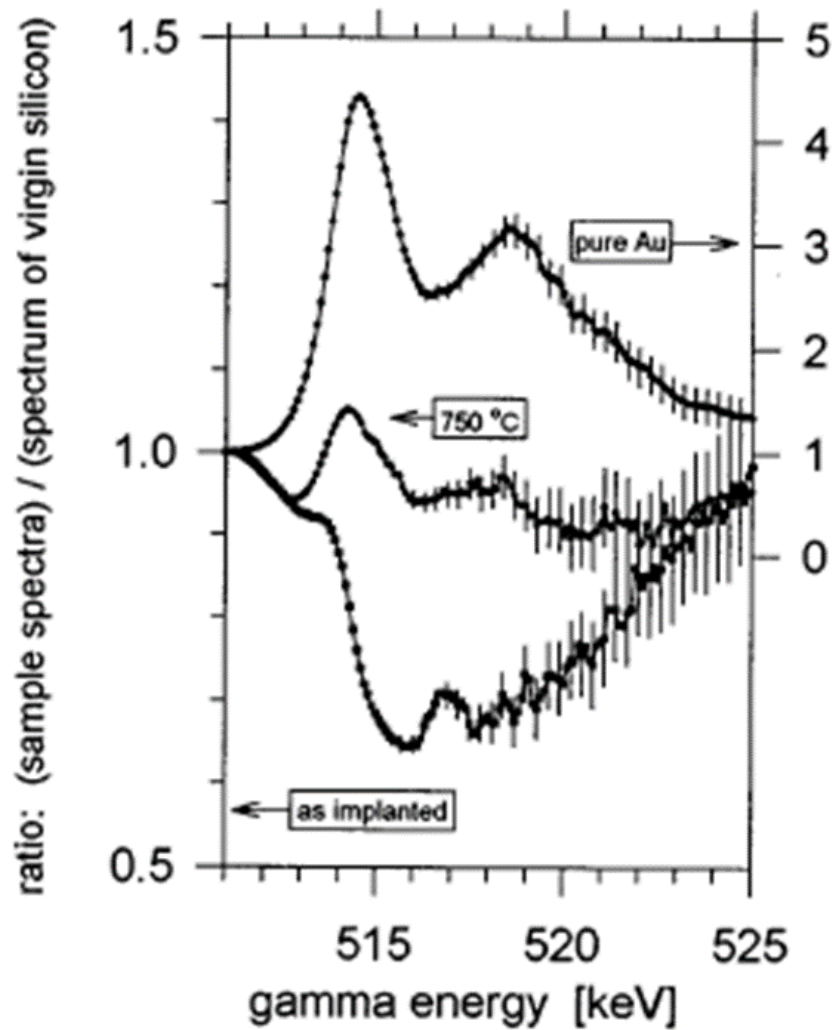
# Measuring vacancy concentrations



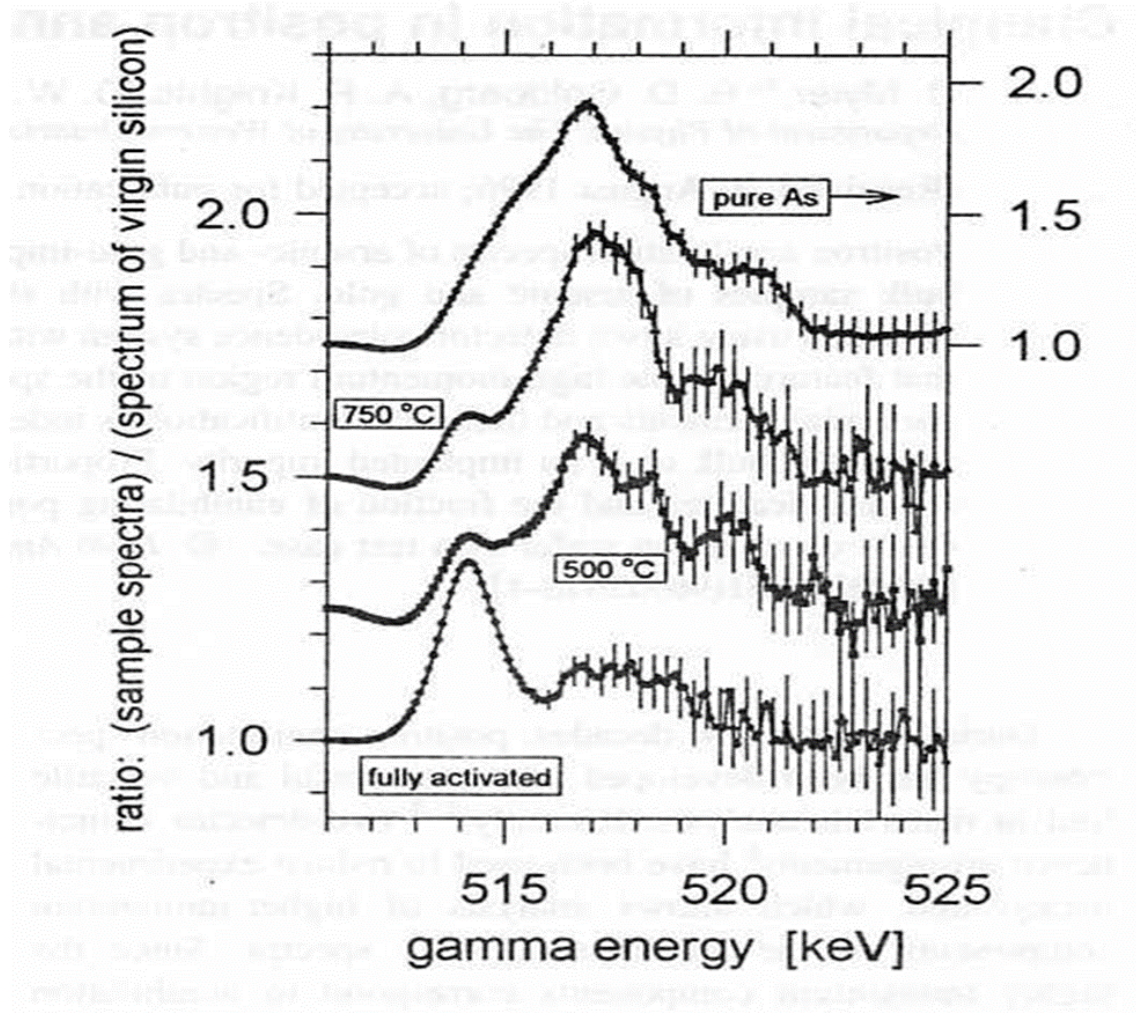
# A closer look at annihilation spectra...



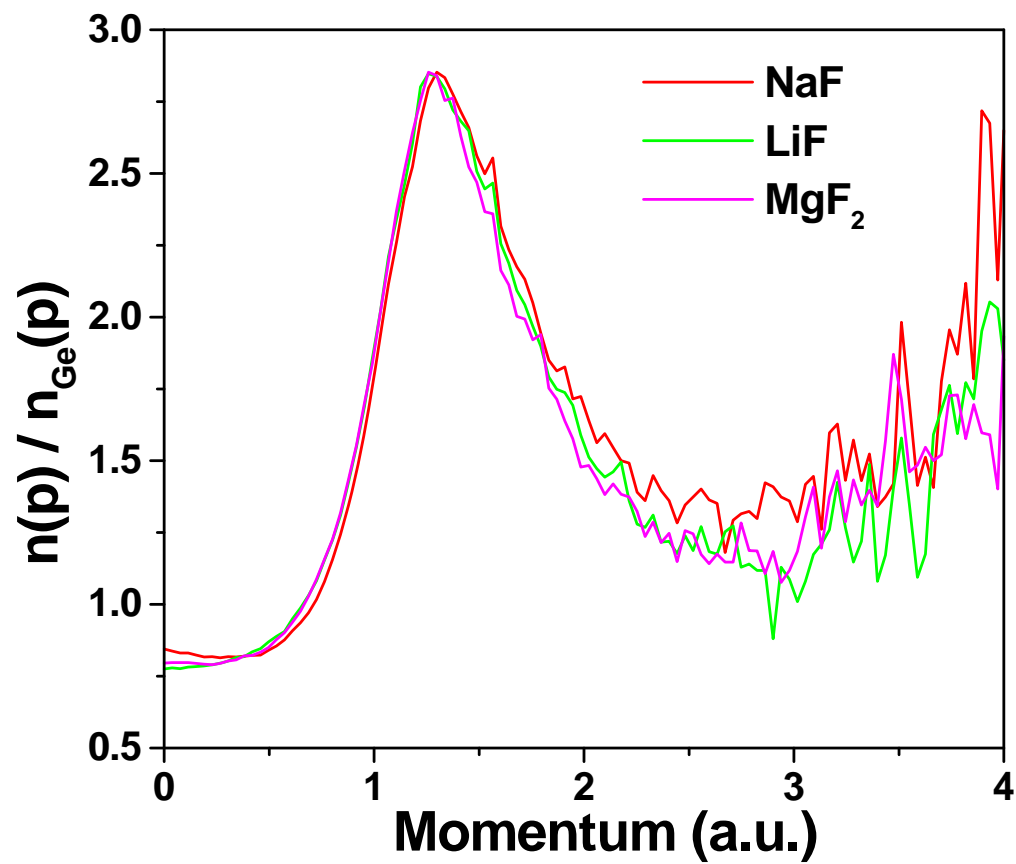
# Chemical “fingerprints”



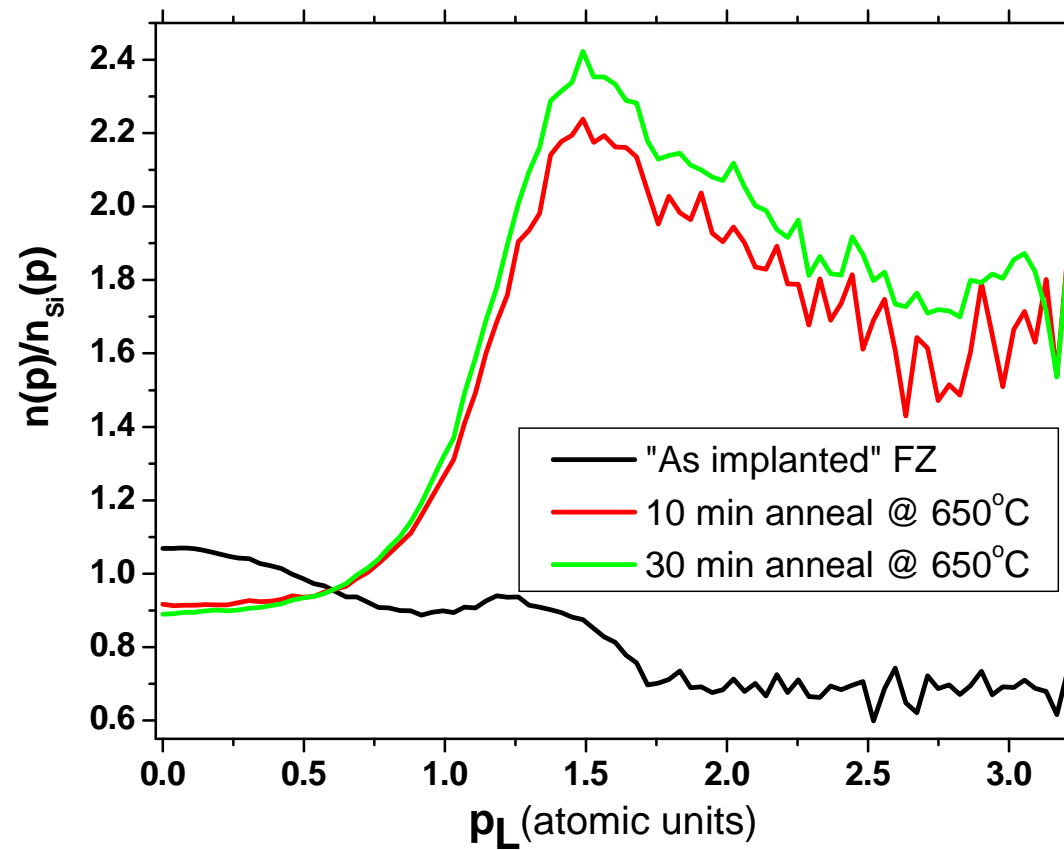
# Arsenic in silicon



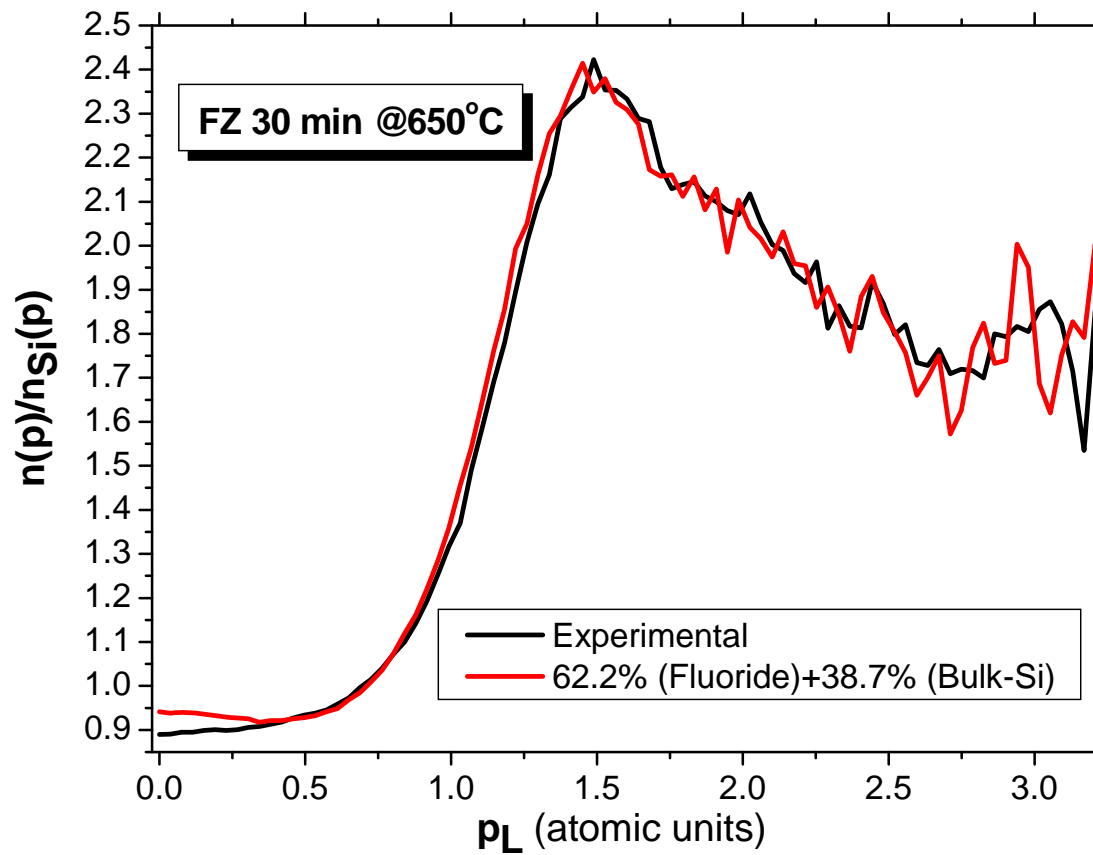
# Various fluorides



# F-doped silicon



# “Reconstruction”

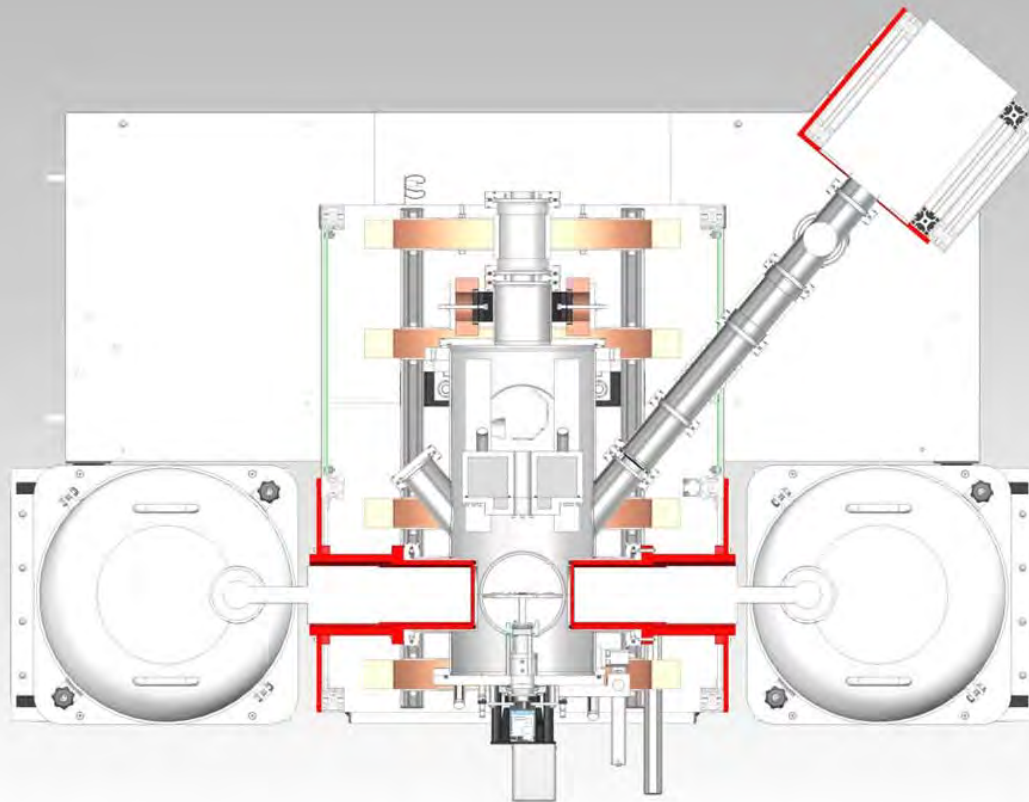




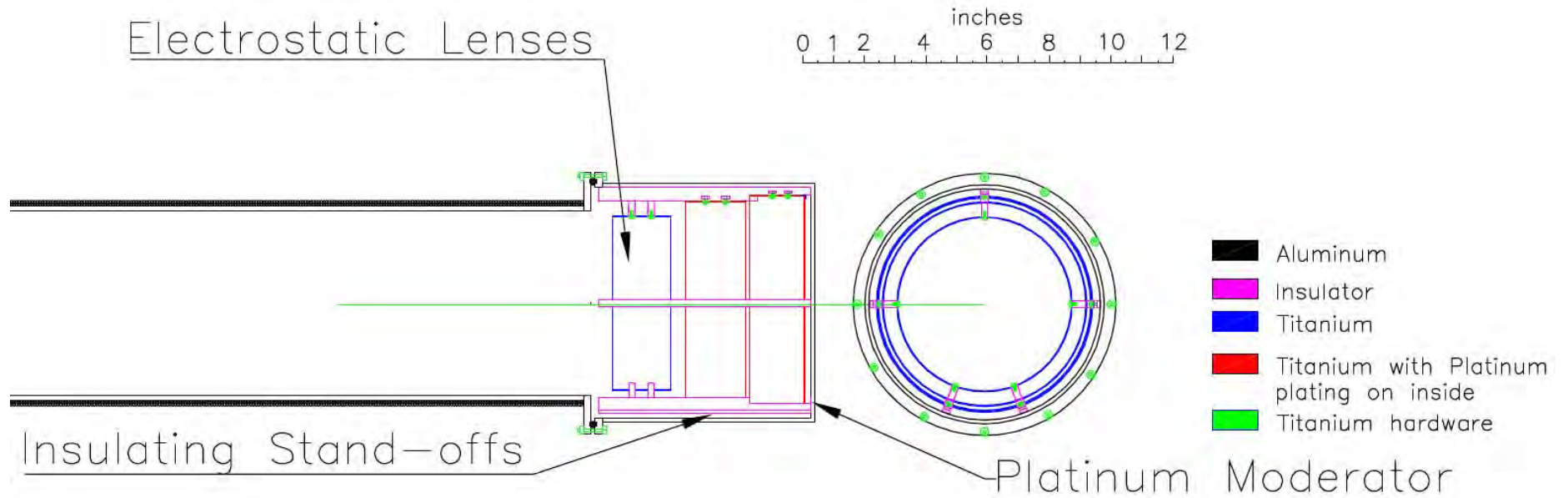
# New apparatus



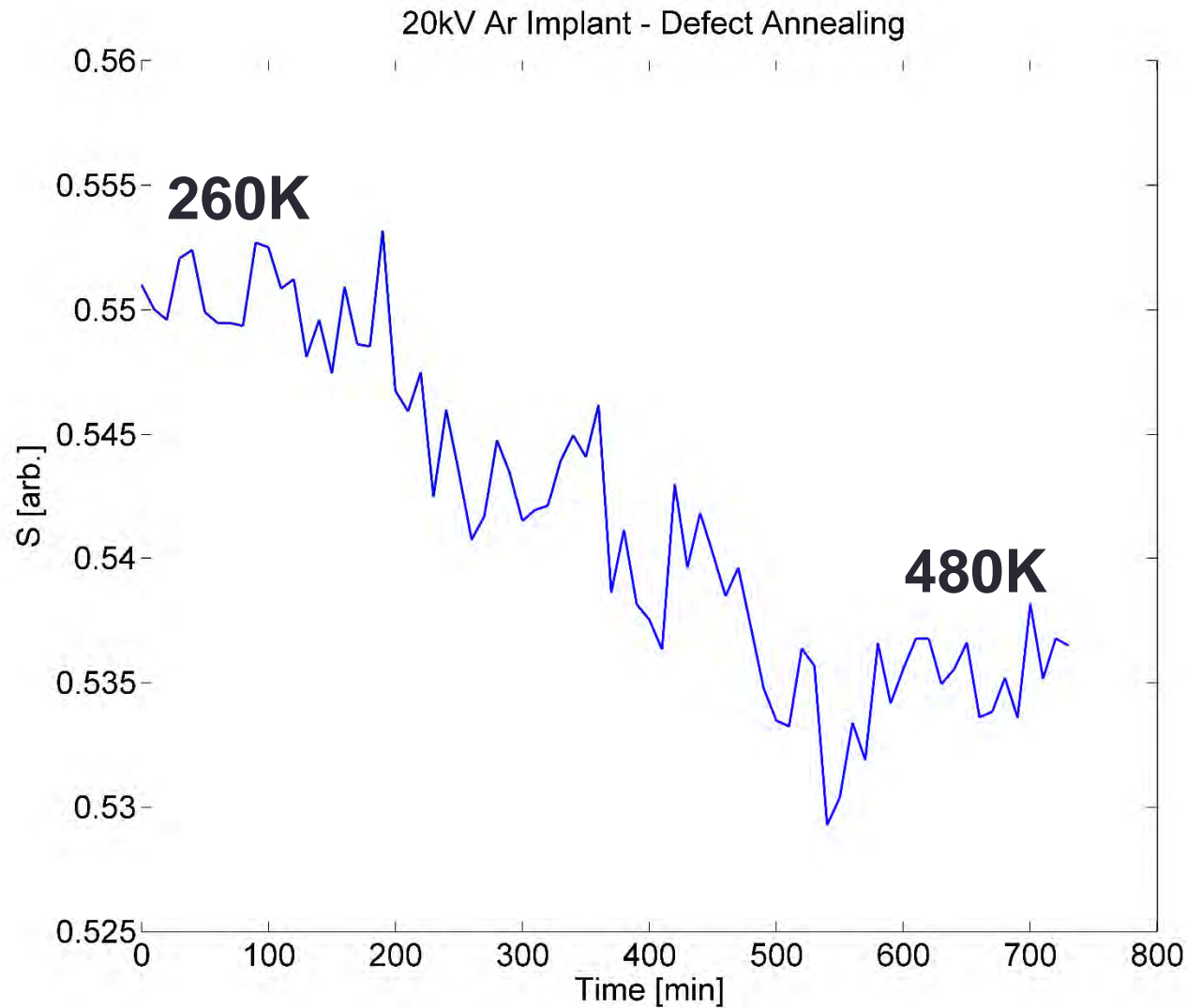
# *In situ* ion implantation/positron spectroscopy



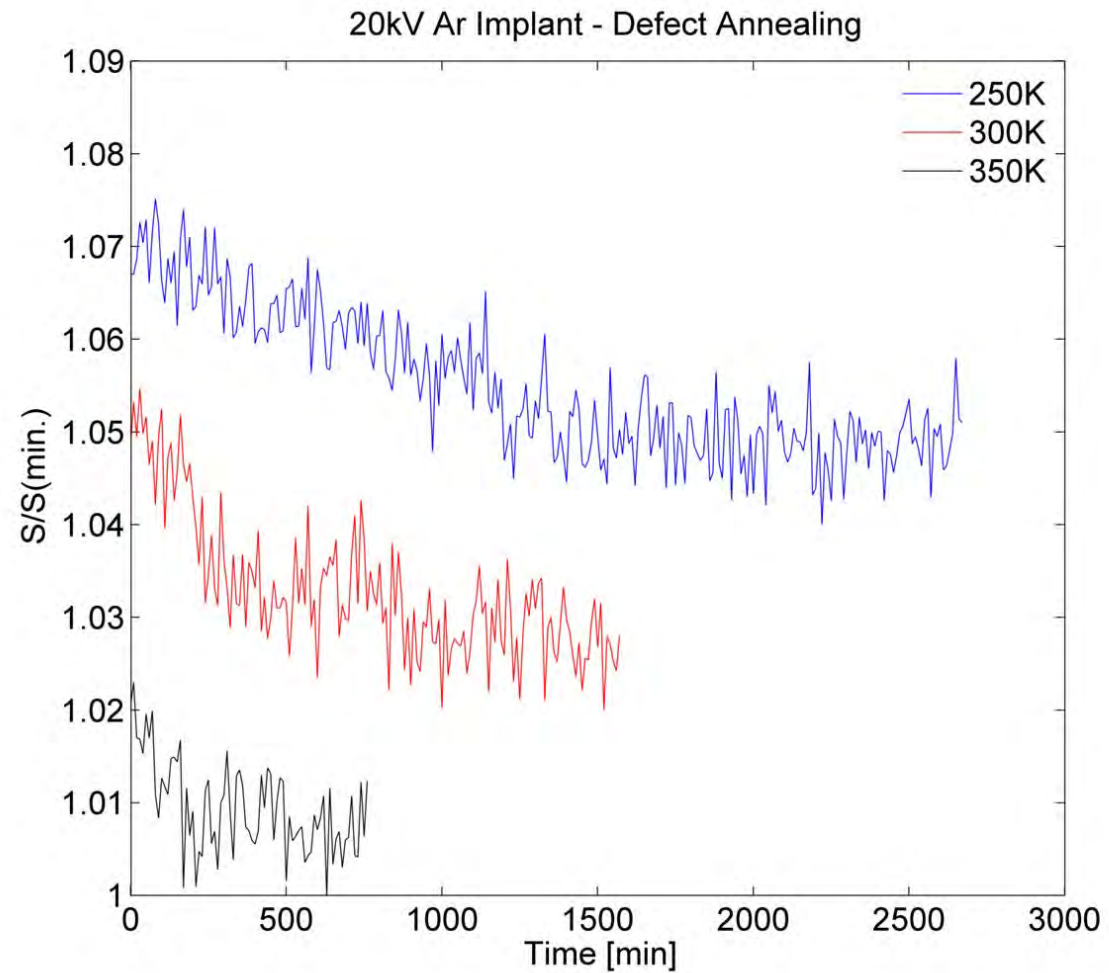
# Positron Source and Moderator (Ti/Pt)



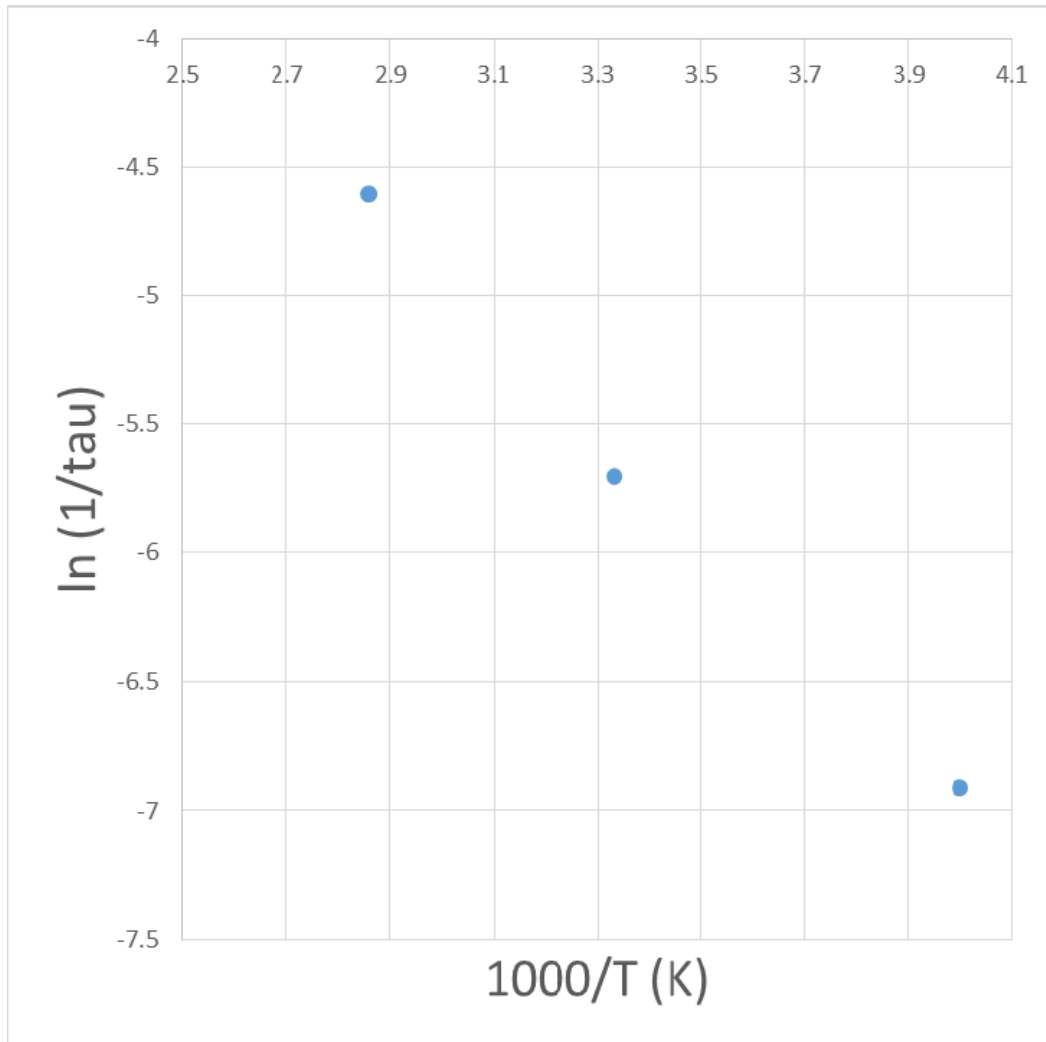
# Ramp annealing of 10keV argon implant 1-5 ohm-cm boron-doped silicon



# Isothermal annealing



# Arrhenius plot

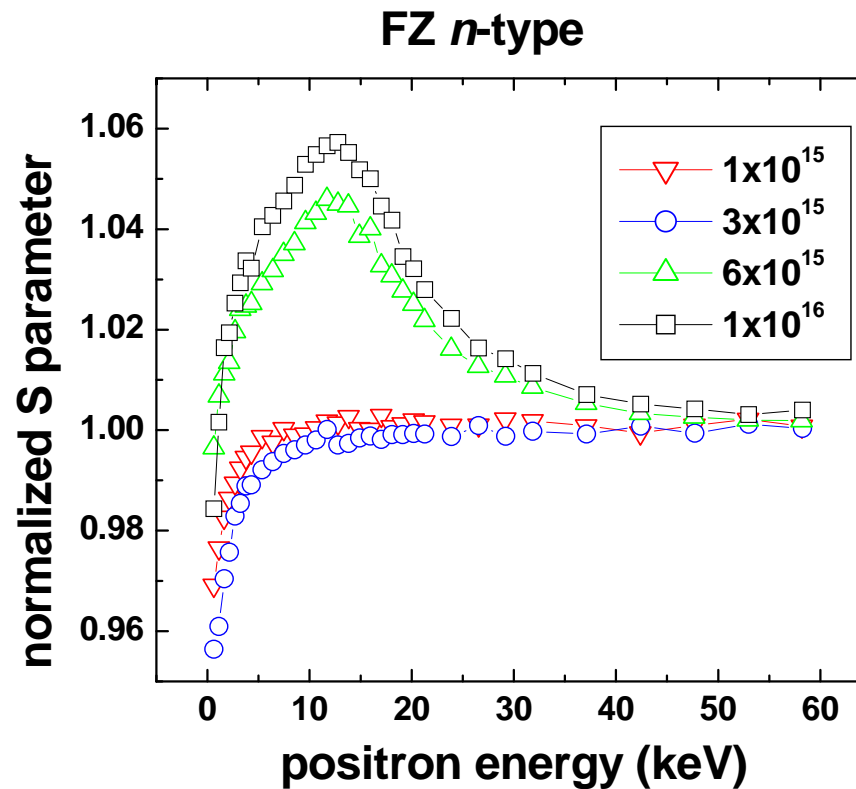


**$E_a \sim 0.2\text{eV}$**

# Summary

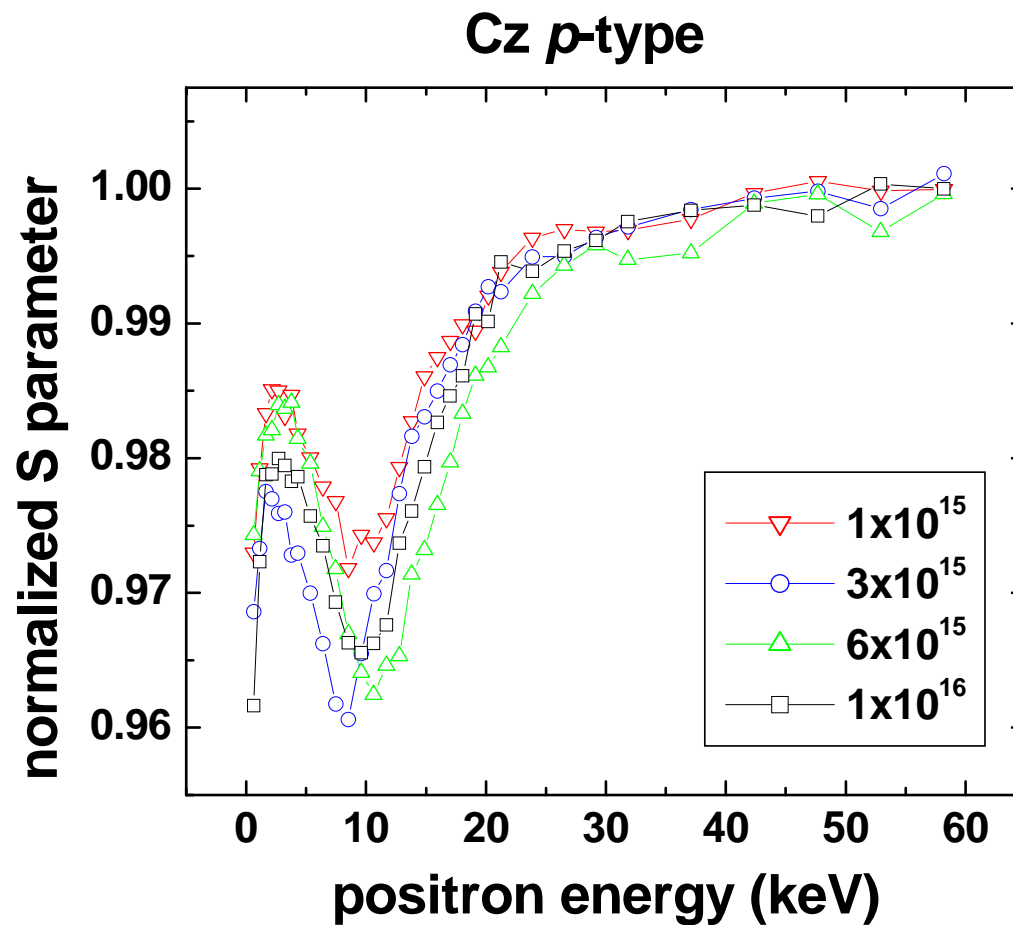
- Interplay among vacancies, interstitials and impurities provides complex microscopic behaviour that drives materials properties
- Positron annihilation can provide pieces of the puzzle to understand this

# Void formation threshold: Implant 325 keV He, anneal 800°C.

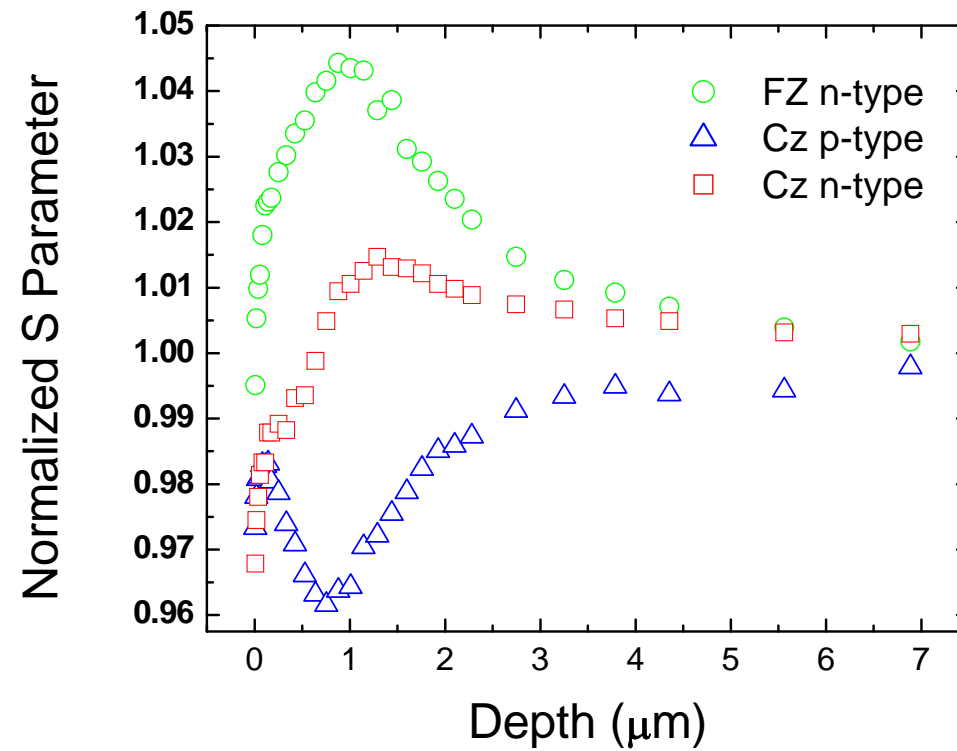




# Void formation threshold

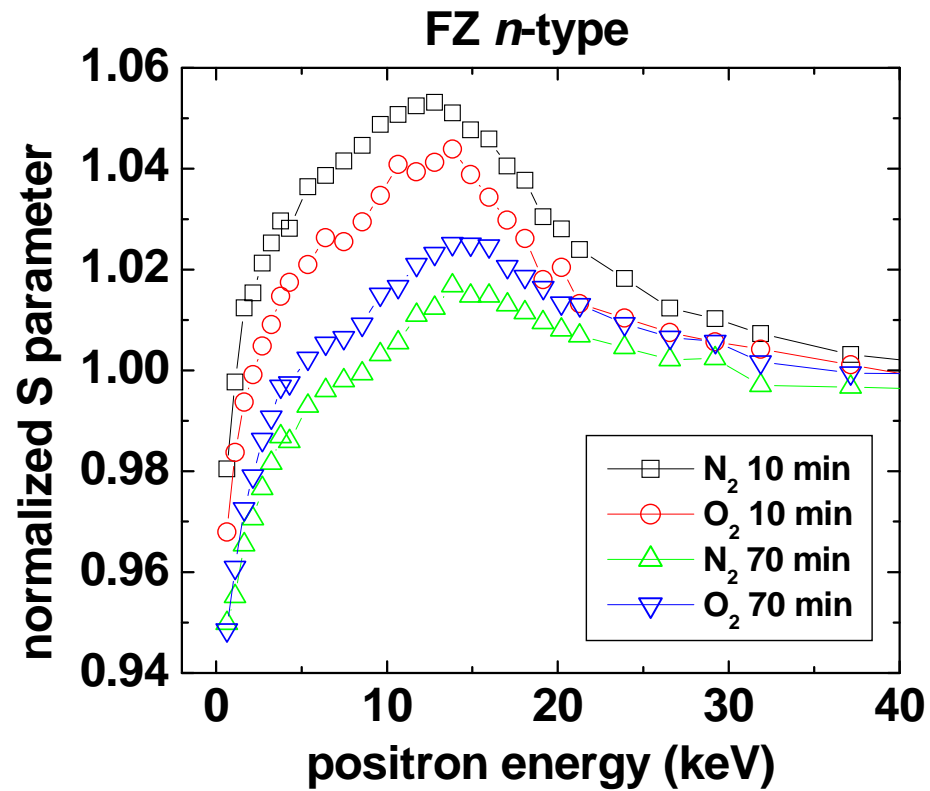


# Void formation threshold





# Annealing ambient



# Applications

- Irradiation
- Aging
- Fatigue
- Thermal history
- Thin film growth
- Porosity
- Semiconductors
- Metals
- Polymers
- Ceramics

# Ion implantation creates vacancies and interstitials, and introduces impurities

